

<b>Notice of References Cited</b>	Application/Control No. 09/851,408	Applicant(s)/Patent Under Reexamination ROTHAAR ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,442,130 B1	08-2002	Jones et al.	370/208
*	B	US-6,081,564 A	06-2000	Han, Deog-Su	375/345
*	C	US-2001/0048727	12-2001	Schmutz et al.	375/345
*	D	US-5,758,271	05-1998	Rich et al.	455/234.1
*	E	US-5,721,756 A	02-1998	Liebetreu et al.	375/344
*	F	US-6,072,998 A	06-2000	Kaku, Tomoya	455/234.2
*	G	US-5,142,695 A	08-1992	Roberts et al.	455/437
*	H	US-6,212,244 B1	04-2001	Davidovici et al.	375/345
*	I	US-3,374,435	03-1968	ENGEL JOEL S	375/349
*	J	US-2002/0142725 A1	10-2002	Clelland et al.	455/63
*	K	US-6,175,270 B1	01-2001	Vannucci, Giovanni	330/2
*	L	US-2003/0232608 A1	12-2003	Yamauchi, Shigeki	455/136
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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